

ABSTRACT OF THE DISCLOSURE

A semiconductor integrated circuit device is disclosed that can provide greater flexibility of layout while essentially ensuring circuit characteristics, and at the same time providing an minimum electrostatic discharge breakdown withstand value according to Charged Device Model (CDM) at all input/output (I/O) terminals. For each I/O terminal a size of a CDM protective device can be optimized in response to reference electric potential wiring resistance between an input protective device, a MOSFETs that can constitute an internal circuit, and an input resistance.